

**Search Notes****Application/Control No.**

10/693,909

**Examiner**

DANH C. LE

**Applicant(s)/Patent under Reexamination**

UMESH ET AL.

**Art Unit**

2683

**SEARCHED**

Class	Subclass	Date	Examiner
455	562.1	7/29/05	DCL
561			
273			
310	334		
	249		
347	757		
342	372		
	373		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

Inventor Name Search 7/29/05 DCL  
(Check for Double Patent)

EAST Search 7/30/05 DCL  
(USP, USPUB)

EAST Search 7/31/05 DCL  
(DERWENT, EPV, JPO)

Lee Nguyen (455)

Han Vuong (455)

Interference Search

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner